Chip Scale Review

2017 Editorial Calendar

(Editorial close date: 11/20)	January • February	* indicates show distribution
Industry forecast		SEMI European 3D Summit Grenoble, France (Jan 23-25) * SMTA Pan Pac Microelectronics Symposium * Kauai, Hawaii (Feb 6-9) SEMICON Korea Seoul, Korea (Feb 8-10) APEX Expo San Diego, CA (Feb 14-16) BiTS Workshop* Mesa, AZ (March 5-8) IMAPS DPC* Fountain Hills, AZ (March 6-9) SEMICON China* Shanghai, China (March 14-16)*
Semiconductor merger & consolidation		
Fan-out packaging		
Metrology for advanced packaging applications		
Packaging photonics		
Plasma dicing		
Electronic assembly reliability		
Test & Burn-in		
Testing of MEMS / sensors in HVM		

International Directory of Test and Burn-in Socket Suppliers

Ad Space Close Jan 6 - Ad Materials Close Jan 11

Wafer bumping 3D integration technology for high-density, high performance ICs Chip-package Interaction Automotive electronic challenges Die attach • SEMICON SE Asia Penang, Malaysia (Apr 25-27) • ECTC * Lake Buena Vista, FL(May 30- June 2)
3D integration technology for high-density, high performance ICs Chip-package Interaction Automotive electronic challenges • ECTC * Lake Buena Vista, FL(May 30- June 2)
Chip-package Interaction Automotive electronic challenges
Die attach
Electronic materials
3D technology failure analysis
Hi density FO package for RF applications
Advances in FOWLP

Ad Space Close Feb 10 - Materials Close Feb 15

(Editorial close date: 3/10)	May • June	* indicates show distribution
Thin wafer handling		IEEE/SW Test Workshop (SWTW) San Diego, CA (June 5-8) Sensors Expo San Jose, CA (June 27-29) SEMICON West * San Francisco, CA (July 12-14)
Wafer probing		
Wafer test		
Adhesives, underfill, encapsulants		
Semiconductor mergers		
Lithography solutions for MEMS		
System in package (SiP)		
Advances in thermal management		
Feature: 50 years of CEA-Leti – past, present, future		

Ad Space Close May 19 - Ad Materials Close May 24